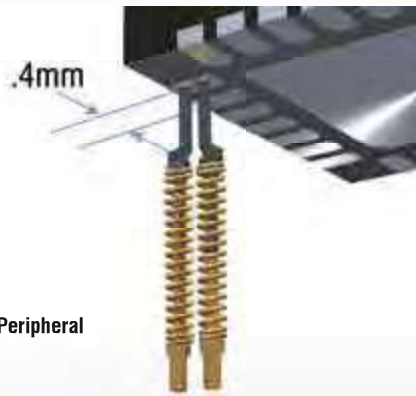


## Z - Kelvin

0.40 mm

### Z-KELVIN

ECT's ZIP® Kelvin .4mm is ideal for voltage sensitive tests on array or peripheral devices requiring milliohm resistance measurements as well as high-power test applications.

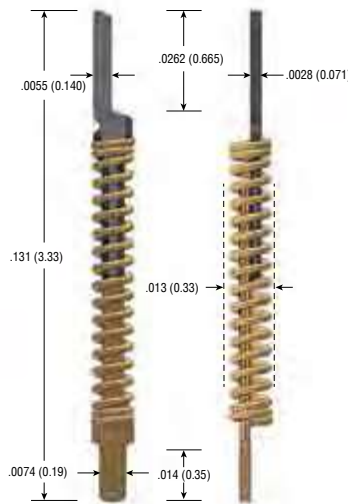


Peripheral



Array

### Z-040KHJ



#### Mechanical

Pitch:	.016 (0.40)
Recommended Travel:	.025 (0.64)
Full Travel:	.028 (0.71)
Test Height:	.105 (2.67)
Mechanical Life*:	500,000 cycles
Operating Temperature:	-55°C to +155°C
Spring Force in oz. (grams):	1.20 (34)

#### Electrical (Static Conditions)

Current Rating DC:	1.2 amps
Average DC Probe Resistance** :	< 70 mOhms
Self Inductance (Ls):	1.0 nH
Capacitance (Cc):	0.40 pF
Bandwidth @ -1dB:	7.0 GHz

#### Materials and Finishes

Plunger DUT:	HyperCore™
Plunger HIB:	BeCu with proprietary plating
Spring:	Stainless Steel, Gold plated

#### Tip Style - DUT

K			
			

#### Tip Style - HIB

J			
			



Dimensions in inches (millimeters). Specifications subject to change without notice. Consult factory for other temperature requirements, and applications below -40°C. Stocking Disclaimer: Stocking levels for part numbers listed in this catalog are subject to change. Availability is based on current levels of usage and demand.



\* Life specifications are based on lab results but are dependent on cleaning frequency and the specific customer application, including DUT materials, handler kit, maintenance, etc.  
\*\* Contact resistance will increase over time due to solder build-up and wear